LDO Linear Regulator - Micropower, DELAY, Adjustable RESET, Sense Output

5.0 V, 3.3 V, 150 mA

The NCV4269A is a $5.0\,\mathrm{V}$ and $3.3\,\mathrm{V}$ precision micropower voltage regulator with an output current capability of $150\,\mathrm{mA}$.

The output voltage is accurate within $\pm 2.0\%$ with a maximum dropout voltage of 0.5 V at 100 mA. Low quiescent current is a feature drawing only 190 μ A with a 1.0 mA load. This part is ideal for any and all battery operated microprocessor equipment.

Microprocessor control logic includes an active reset output RO with delay and a SI/SO monitor which can be used to provide an early warning signal to the microprocessor of a potential impending reset signal. The use of the SI/SO monitor allows the microprocessor to finish any signal processing before the reset shuts the microprocessor down.

The active Reset circuit operates correctly at an output voltage as low as 1.0 V. The Reset function is activated during the power up sequence or during normal operation if the output voltage drops outside the regulation limits.

The reset threshold voltage can be decreased by the connection of an external resistor divider to the R_{ADJ} lead. The regulator is protected against reverse battery, short circuit, and thermal overload conditions. The device can withstand load dump transients making it suitable for use in automotive environments. The device has also been optimized for EMC conditions.

Features

- 5.0 V and 3.3 V Output Voltage Options, ± 2.0% Accuracy
- Low 190 µA Quiescent Current
- Active Reset Output Low Down to $V_0 = 1.0 \text{ V}$
- Adjustable Reset Threshold
- 150 mA Output Current Capability
- Fault Protection
 - ♦ +60 V Peak Transient Voltage
 - → -40 V Reverse Voltage
 - Short Circuit
 - Thermal Overload
- Early Warning through SI/SO Leads
- Internally Fused Leads in SO-14 and SO-20 Packages
- Integrated Pullup Resistor at Logic Outputs (To Use External Resistors, Select the NCV4279A)
- Very Low Dropout Voltage
- Electrical Parameters Guaranteed Over Entire Temperature Range
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These are Pb-Free Devices



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SO-8 D1 SUFFIX CASE 751





SO-8 EXPOSED PAD PD SUFFIX CASE 751AC



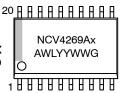


SO-14 D2 SUFFIX CASE 751A





SO-20 DW SUFFIX CASE 751D



X = 5 (5.0 V Output) = 3 (3.3 V Output)

= Assembly Location

WL, L = Wafer Lot YY, Y = Year WW, W = Work Week $G, \bullet = Pb Free$

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 16 of this data sheet.

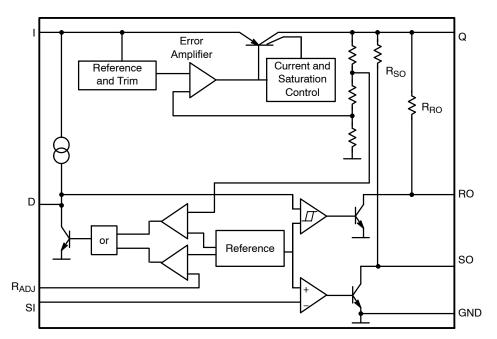
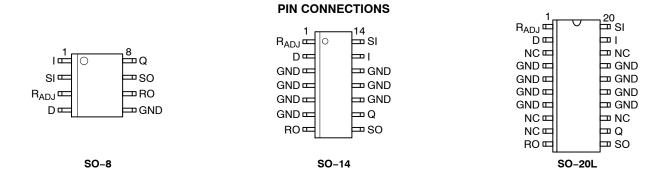


Figure 1. Block Diagram



PACKAGE PIN DESCRIPTION

	Package Pin Number				
SO-8	SO-8 EP	SO-14	SO-20L	Pin Symbol	Function
3	3	1	1	R _{ADJ}	Reset Threshold Adjust; if not used to connect to GND.
4	4	2	2	D	Reset Delay; To Set Time Delay, Connect to GND with Capacitor
5	5	3, 4, 5, 6, 10, 11, 12	4, 5, 6, 7, 14, 15, 16, 17	GND	Ground
-	_	-	3, 8, 9, 13, 18	NC	No connection to these pins from the IC.
6	6	7	10	RO	Reset Output; The Open–Collector Output has a 20 $k\Omega$ Pullup Resistor to Q. Leave Open if Not Used.
7	7	8	11	SO	Sense Output; This Open–Collector Output is Internally Pulled Up by 20 k Ω pullup resistor to Q. If not used, keep open.
8	8	9	12	Q	5 V or 3.3 V Output; Connect to GND with a 10 μF Capacitor, ESR < 5 Ω
1	1	13	19	1	Input; Connect to GND Directly at the IC with a Ceramic Capacitor.
2	2	14	20	SI	Sense Input; If not used, Connect to Q.
_	EPAD	_	-	EPAD	Connect to ground potential or leave unconnected

MAXIMUM RATINGS ($T_J = -40^{\circ}C$ to 150°C)

Parameter	Symbol	Min	Max	Unit
Input to Regulator	V _I I _I	-40 Internally Limited	45 Internally Limited	V
Input Transient to Regulator	VI	-	60	V
Sense Input	V _{SI} I _{SI}	-40 -1	45 1	V mA
Reset Threshold Adjust	V _{RADJ} I _{RADJ}	-0.3 -10	7 10	V mA
Reset Delay	V _D I _D	-0.3 Internally Limited	7 Internally Limited	V
Ground	Ιq	50	-	mA
Reset Output	V _{RO} I _{RO}	-0.3 Internally Limited	7 Internally Limited	V
Sense Output	V _{SO} I _{SO}	-0.3 Internally Limited	7 Internally Limited	V
Regulated Output	V _Q I _Q	-0.5 -10	7.0 -	V mA
Junction Temperature Storage Temperature	T _J T _{STG}	- -50	150 150	°C °C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

RECOMMENDED OPERATING RANGE

Input Voltage Operating Range 5.0 Version 3.3 Version	VI	5.5 4.4	45 45	V
Junction Temperature Operating Range	TJ	-40	150	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

LEAD TEMPERATURE SOLDERING AND MSL

Parameter	Symbol	Value
MSL, 20-Lead LS Temperature 265°C Peak (Note 3)	MSL	3
MSL, 8-Lead, 14-Lead, LS Temperature 265°C Peak (Note 3)	MSL	1
MSL, 8-Lead EP, LS Temperature 260°C	MSL	2

This device series incorporates ESD protection and exceeds the following ratings: Human Body Model (HBM) ≤ 4.0 kV per AEC-Q100-002. Machine Model (MM) ≤ 200 V per AEC-Q100-003.

^{2.} Latchup Current Maximum Rating: \leq 150 mA per AEC-Q100-004. 3. +5°C/-0°C, 40 Sec Max-at-Peak, 60 - 150 Sec above 217°C.

THERMAL CHARACTERISTICS

Characteristic	Test Conditions (Typical Values)	Unit
SO-8 Package (Note 4)	<u> </u>	•
Junction–to–Pin 4 (Ψ – JL4, Ψ _{L4})	53.8	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA}$, θ_{JA})	170.9	°C/W
SO-8 EP Package (Note 4)		
Junction–to–Pin 8 (Ψ – JL8, Ψ_{L8})	23.7	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA}$, θ_{JA})	71.4	°C/W
Junction-to-Pad (Ψ - JPad)	7.7	°C/W
SO-14 Package (Note 4)		
Junction-to-Pin 4 (Ψ – JL4, Ψ _{L4})	18.4	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA},\theta_{JA}$)	111.6	°C/W
SO-20 Package (Note 4)		
Junction–to–Pin 4 (Ψ – JL4, Ψ _{L4})	21.8	°C/W
Junction-to-Ambient Thermal Resistance ($R_{\theta JA},\theta_{JA}$)	95.3	°C/W

^{4. 2} oz copper, 50 mm² copper area, 1.5 mm thick FR4

ELECTRICAL CHARACTERISTICS ($-40^{\circ}C \le T_{J} \le 150^{\circ}C$, V_{I} = 13.5 V unless otherwise specified)

Characteristic	Symbol	Test Conditions	Min	Тур	Max	Unit
REGULATOR	•		•		•	•
Output Voltage (5.0 V Version)	VQ	1 mA \leq I _Q \leq 100 mA, 6 V \leq V _I \leq 16 V	4.90	5.00	5.10	٧
Output Voltage (3.3 V Version)	VQ	1 mA \leq I _Q \leq 100 mA, 5.5 V \leq V _I \leq 16 V	3.234	3.30	3.366	V
Current Limit	IQ	-	150	200	500	mA
Current Consumption; I _q = I _I - I _Q	Iq	I _Q = 1 mA, RO, SO High	-	190	250	μΑ
Current Consumption; $I_q = I_I - I_Q$	Iq	I _Q = 10 mA, RO, SO High	-	250	450	μΑ
Current Consumption; $I_q = I_I - I_Q$	Iq	I _Q = 50 mA, RO, SO High	-	2.0	3.0	mA
Dropout Voltage (5.0 V Version)	V _{dr}	V _I = 5 V, I _Q = 100 mA	-	0.25	0.5	V
Load Regulation	ΔV_{Q}	I _Q = 5 mA to 100 mA	-	10	20	mV
Line Regulation	ΔV_{Q}	V _I = 6 V to 26 V I _Q = 1 mA	-	10	30	mV
RESET GENERATOR						
Reset Switching Threshold 5.0 V Version 3.3 V Version	V _{RT}	- -	4.50 2.97	4.65 3.07	4.80 3.17	٧
Reset Adjust Switching Threshold 5.0 V Version 3.3 V Version	$V_{RADJ,TH}$	V _Q > 3.5 V V _Q > 2.3 V	1.26 1.26	1.35 1.35	1.44 1.44	٧
Reset Pullup Resistance	R _{RO,INT}	-	10	20	40	kΩ
Reset Output Saturation Voltage	V _{RO,SAT}	V _Q < V _{RT} , R _{RO, INT}	-	0.1	0.4	V
Upper Delay Switching Threshold 5.0 V Version 3.3 V Version	V _{UD}	- -	1.4 0.7	1.8 1.23	2.2 1.6	٧
Lower Delay Switching Threshold 5.0 V Version 3.3 V Version	V _{LD}	- -	0.3 0.3	0.45 0.49	0.60 0.60	٧
Saturation Voltage on Delay Capacitor	$V_{D,SAT}$	V _Q < V _{RT}	-	-	0.1	V
Charge Current 5.0 V Version 3.3 V Version	I _{D,C}	V _D = 1 V V _D = 1 V	3.0 3.0	6.5 4.3	9.5 7.0	μΑ
Delay Time L → H	t _d	C _D = 100 nF	17	28	73	ms
Delay Time H → L	t _{RR}	C _D = 100 nF	-	3.15	-	μs
INPUT VOLTAGE SENSE						
Sense Threshold High	$V_{SI,High}$	-	1.24	1.31	1.38	V
Sense Threshold Low	V _{SI,Low}	-	1.16	1.20	1.28	٧
Sense Output Saturation Voltage	V _{SO,Low}	V _{SI} < 1.20 V; V _Q > 3 V; R _{SO}	-	0.1	0.4	٧
Sense Resistor Pullup	R _{SO,INT}	-	10	20	40	kΩ
Sense Input Current	I _{SI}	-	-1.0	0.1	1.0	μΑ

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

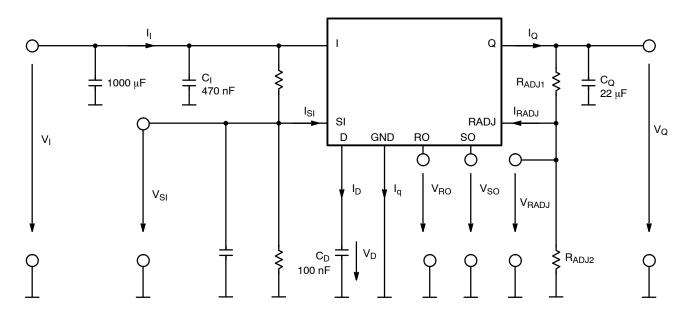


Figure 2. Measuring Circuit

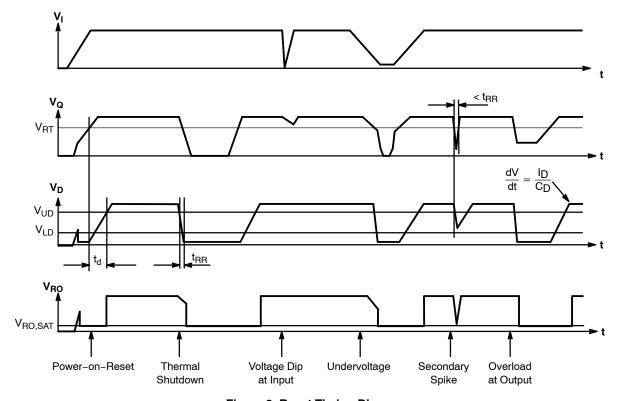


Figure 3. Reset Timing Diagram

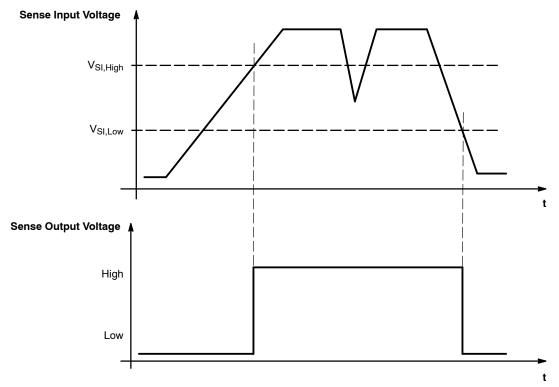


Figure 4. Sense Timing Diagram

TYPICAL PERFORMANCE CHARACTERISTICS - 5.0 V OPTION

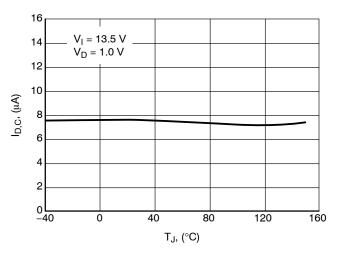


Figure 5. Charge Current $I_{D,C}$ vs. Temperature T_J

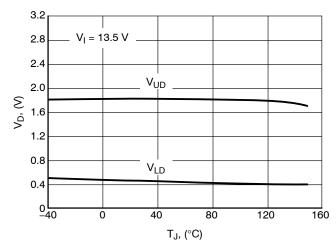


Figure 6. Switching Voltage V_{UD} and V_{LD} vs. Temperature $\boldsymbol{T_J}$

TYPICAL PERFORMANCE CHARACTERISTICS - 5.0 V OPTION

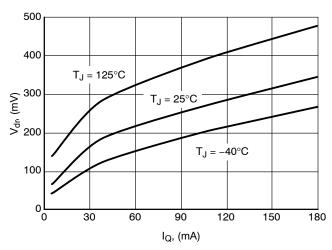


Figure 7. Drop Voltage V_{dr} vs. Output Current I_Q

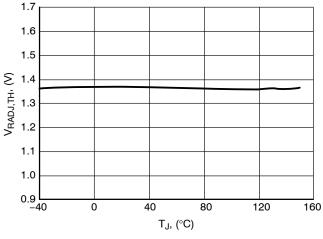


Figure 8. Reset Adjust Switching Threshold, $V_{RADJ,TH}$ vs. Temperature T_J

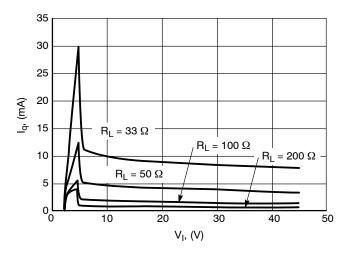


Figure 9. Current Consumption I_q vs. Input Voltage V_l

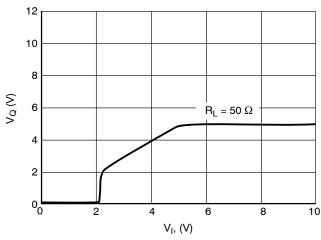


Figure 10. Output Voltage V_Q vs. Input Voltage V_I

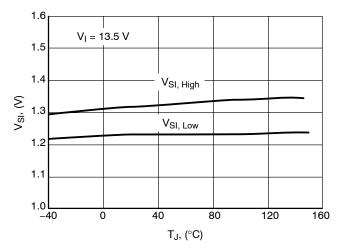


Figure 11. Sense Threshold V_{SI} vs. Temperature T_{J}

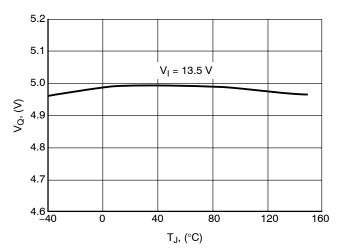


Figure 12. Output Voltage V_Q vs. Temperature T_J

TYPICAL PERFORMANCE CHARACTERISTICS - 5.0 V OPTION

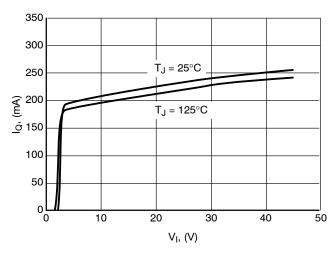


Figure 13. Output Current Limit I_Q vs. Input Voltage V_I

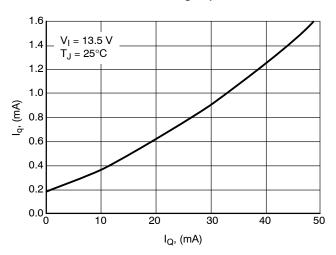


Figure 15. Current Consumption I_q vs. Output Current I_Q

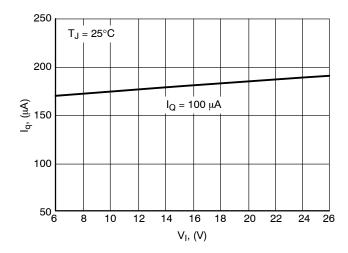


Figure 17. Quiescent Current Iq vs. Input Voltage VI

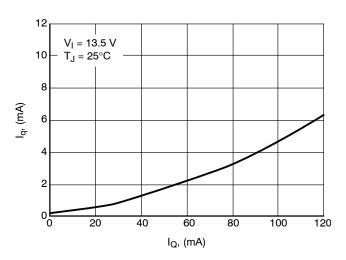


Figure 14. Current Consumption I_q vs. Output Current I_Q

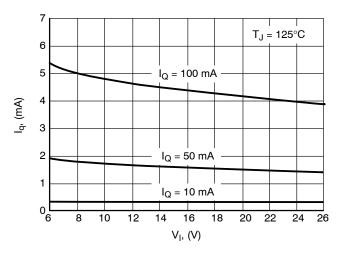


Figure 16. Quiescent Current I_q vs. Input Voltage V_I

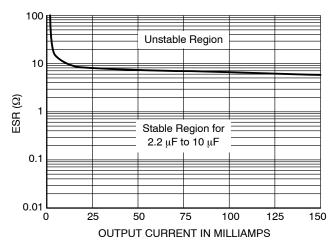


Figure 18. Output Stability, Capacitance ESR vs. Output Load Current

TYPICAL PERFORMANCE CHARACTERISTICS - 3.3 V OPTION

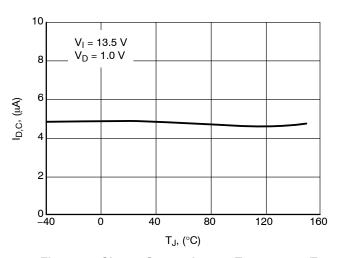


Figure 19. Charge Current $I_{D,C}$ vs. Temperature T_J

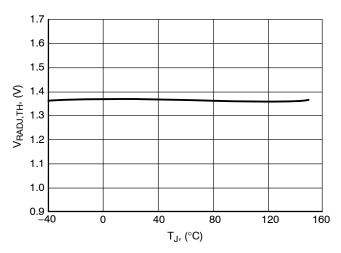


Figure 21. Reset Adjust Switching Threshold, $V_{RADJ,TH}$ vs. Temperature T_J

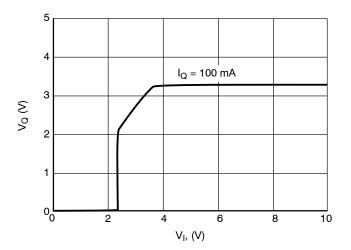


Figure 23. Output Voltage V_Q vs. Input Voltage V_I

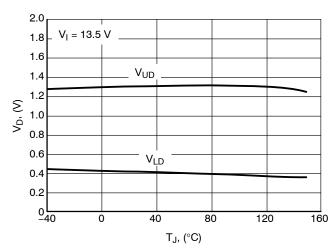


Figure 20. Switching Voltage V_{UD} and V_{LD} vs. Temperature T_J

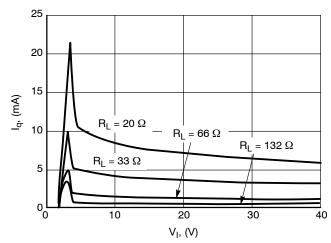


Figure 22. Current Consumption I_q vs. Input Voltage V_I

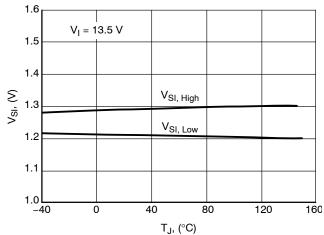


Figure 24. Sense Threshold V_{SI} vs. Temperature T_{J}

TYPICAL PERFORMANCE CHARACTERISTICS - 3.3 V OPTION

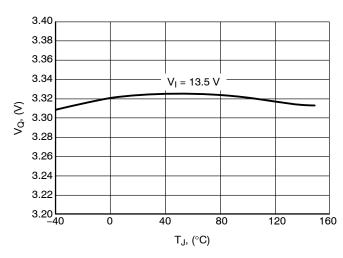


Figure 25. Output Voltage V_Q vs. Temperature T_J

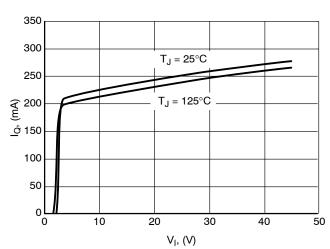


Figure 26. Output Current Limit I_Q vs. Input Voltage V_I

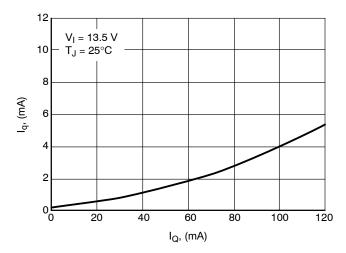


Figure 27. Current Consumption I_q vs. Output Current I_Q

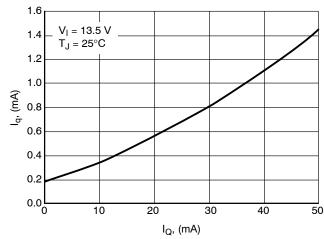


Figure 28. Current Consumption I_q vs. Output Current I_Q

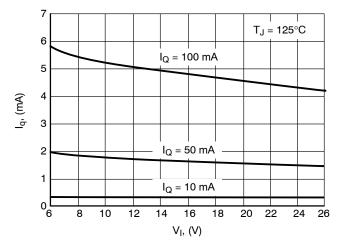


Figure 29. Quiescent Current I_q vs. Input Voltage V_I

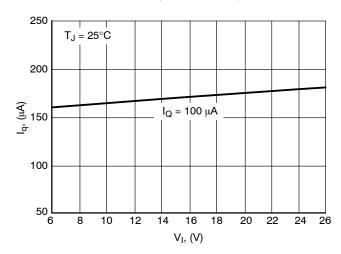


Figure 30. Quiescent Current I_q vs. Input Voltage V_I

TYPICAL PERFORMANCE CHARACTERISTICS - 3.3 V OPTION

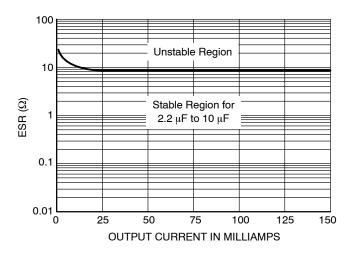


Figure 31. Output Stability, Capacitance ESR vs. Output Load Current

TYPICAL THERMAL CHARACTERISTICS

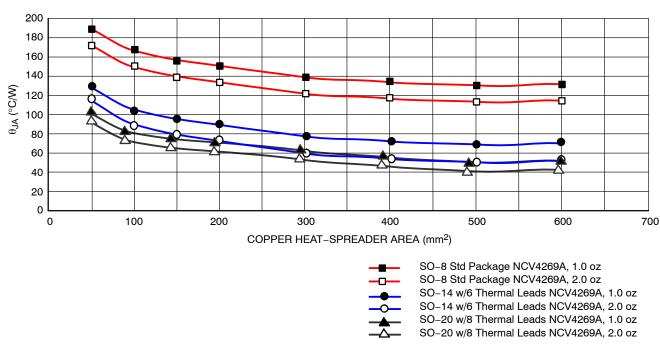


Figure 32. Junction–to–Ambient Thermal Resistance (θ_{JA}) vs. Heat Spreader Area

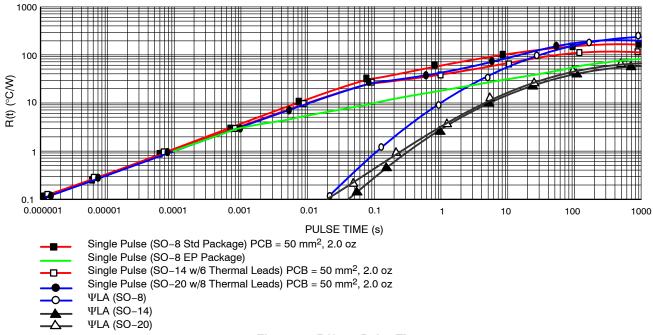


Figure 33. R(t) vs. Pulse Time

APPLICATION DESCRIPTION

OUTPUT REGULATOR

The output is controlled by a precision trimmed reference. The PNP output has base drive quiescent current control for regulation while the input voltage is low, preventing over saturation. Current limit and voltage monitors complement the regulator design to give safe operating signals to the processor and control circuits.

RESET OUTPUT (RO)

A reset signal, Reset Output, RO, (low voltage) is generated as the IC powers up. After the output voltage V_Q increases above the reset threshold voltage V_{RT} , the delay timer D is started. When the voltage on the delay timer V_D passes V_{UD} , the reset signal RO goes high. A discharge of the delay timer V_D is started when V_Q drops and stays below the reset threshold voltage V_{RT} . When the voltage of the delay timer V_D drops below the lower threshold voltage V_{LD} the reset output voltage V_{RO} is brought low to reset the processor.

The reset output RO is an open collector NPN transistor with an internal 20 $k\Omega$ pullup resistor connected to the output Q, controlled by a low voltage detection circuit. The circuit is functionally independent of the rest of the IC, thereby guaranteeing that RO is valid for $V_{\rm O}$ as low as 1.0 V.

RESET ADJUST (RADJ)

The reset threshold V_{RT} can be decreased from a typical value of 4.65 V (3.04 V for 3.3 V Version) to as low as 3.5 V (2.3 V for 3.3 V Version) by using an external voltage divider connected from the Q lead to the pin R_{ADJ} , as shown in Figure 34. The resistor divider keeps the voltage above the $V_{RADJ,TH}$ (typical 1.35 V) for the desired input voltages, and overrides the internal threshold detector. Adjust the voltage divider according to the following relationship:

$$V_{RT} = V_{RADJ,TH} \cdot (R_{ADJ1} + R_{ADJ2}) / R_{ADJ2}$$
 (eq. 1)

If the reset adjust option is not needed, the R_{ADJ} pin should be connected to GND causing the reset threshold to go to its default value.

RESET DELAY (D)

The reset delay circuit provides a delay (programmable by capacitor C_D) on the reset output lead RO. The delay lead D provides charge current $I_{D,C}$ (typically 6.5 μ A for 5 V Version or 4.3 μ A for 3.3 V Version) to the external delay capacitor C_D during the following times:

- 1. During Powerup (once the regulation threshold has been exceeded).
- 2. After a reset event has occurred and the device is back in regulation. The delay capacitor is set to discharge when the regulation (V_{RT} , reset threshold voltage) has been violated. When the delay capacitor discharges to V_{LD} , the reset signal RO pulls low.

SETTING THE DELAY TIME

The delay time is set by the delay capacitor C_D and the charge current I_D . The time is measured by the delay capacitor voltage charging from the low level of V_{DSAT} to the higher level V_{UD} . The time delay follows the equation:

$$t_d = [C_D (V_{UD} - V_{D, SAT})]/I_{D, C}$$
 (eq. 2)

Example (5 V Version):

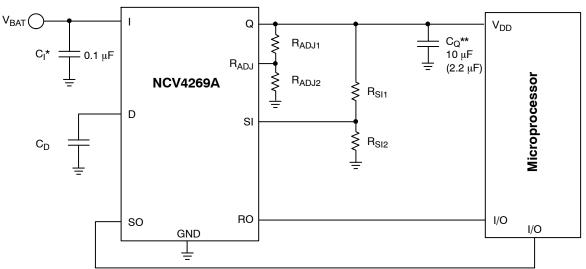
Using $C_D = 100 \text{ nF}$.

Use the typical value for $V_{D,SAT} = 0.1 \text{ V}$.

Use the typical value for $V_{\rm UD} = 1.8 \text{ V}$.

Use the typical value for Delay Charge Current $I_D = 6.5 \mu A$.

$$t_d = [100 \text{ nF} (1.8 - 0.1 \text{ V})]/6.5 \,\mu\text{A} = 26.2 \,\text{ms}$$
 (eq. 3)



^{*}C_I required if regulator is located far from the power supply filter.

Figure 34. Application Diagram

^{**} C_Q – minimum cap required for stability is 2.2 μ F while higher over/under–shoots may be expected. Cap must operate at minimum temperature expected.

SENSE INPUT (SI) / SENSE OUTPUT (SO) VOLTAGE MONITOR

An on–chip comparator is available to provide early warning to the microprocessor of a possible reset signal (Figure 4). The output is from an open collector driver with an internal $20~k\Omega$ pull up resistor to output Q. The reset signal typically turns the microprocessor off instantaneously. This can cause unpredictable results with the microprocessor. The signal received from the SO pin will allow the microprocessor time to complete its present task before shutting down. This function is performed by a comparator referenced to the band gap voltage. The actual trip point can be programmed externally using a resistor divider to the input monitor SI (Figure 34). The values for R_{SI1} and R_{SI2} are selected for a typical threshold of 1.20~V on the SI Pin.

SIGNAL OUTPUT

Figure 35 shows the SO Monitor timing waveforms as a result of the circuit depicted in Figure 34. As the output voltage (V_Q) falls, the monitor threshold ($V_{SI,Low}$), is crossed. This causes the voltage on the SO output to go low sending a warning signal to the microprocessor that a reset signal may occur in a short period of time. $T_{WARNING}$ is the time the microprocessor has to complete the function it is currently working on and get ready for the reset shutdown signal. When the voltage on the SO goes low and the RO stays high the current consumption is typically 560 μ A at 1 mA load current.

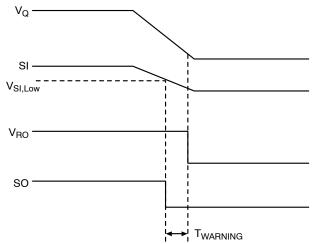


Figure 35. SO Warning Waveform Time Diagram

STABILITY CONSIDERATIONS

The input capacitor C_I in Figure 34 is necessary for compensating input line reactance. Possible oscillations caused by input inductance and input capacitance can be damped by using a resistor of approximately $1.0~\Omega$ in series with C_I .

The output or compensation capacitor helps determine three main characteristics of a linear regulator: startup delay, load transient response and loop stability.

The capacitor value and type should be based on cost, availability, size and temperature constraints. The aluminum electrolytic capacitor is the least expensive solution, but, if the circuit operates at low temperatures

(-25°C to -40°C), both the value and ESR of the capacitor will vary considerably. The capacitor manufacturer's data sheet usually provides this information.

The 10 μF output capacitor C_Q shown in Figure 34 should work for most applications; however, it is not necessarily the optimized solution. Stability is guaranteed at C_Q is min 2.2 μF and max ESR is 10 Ω . There is no min ESR limit which was proved with MURATA's ceramic caps GRM31MR71A225KA01 (2.2 μF , 10 V, X7R, 1206) and GRM31CR71A106KA01 (10 μF , 10 V, X7R, 1206) directly soldered between output and ground pins.

CALCULATING POWER DISSIPATION IN A SINGLE OUTPUT LINEAR REGULATOR

The maximum power dissipation for a single output regulator (Figure 34) is:

PD(max) = [VI(max) - VQ(min)]IQ(max) + VI(max)Iq (eq. 4) where:

 $V_{I(max)}$ is the maximum input voltage,

 $V_{Q(min)}$ is the minimum output voltage,

 $I_{Q(max)}$ is the maximum output current for the application, and I_q is the quiescent current the regulator consumes at $I_{Q(max)}$.

Once the value of $P_{D(max)}$ is known, the maximum permissible value of $R_{\theta JA}$ can be calculated:

$$R_{\theta JA} = (150^{\circ}C - T_A) / P_D$$
 (eq. 5)

The value of $R_{\theta JA}$ can then be compared with those in the package section of the data sheet. Those packages with $R_{\theta JA}$'s less than the calculated value in equation 2 will keep the die temperature below 150°C. In some cases, none of the packages will be sufficient to dissipate the heat generated by the IC, and an external heatsink will be required. The current flow and voltages are shown in the Measurement Circuit Diagram.

HEATSINKS

A heatsink effectively increases the surface area of the package to improve the flow of heat away from the IC and into the surrounding air.

Each material in the heat flow path between the IC and the outside environment will have a thermal resistance. Like series electrical resistances, these resistances are summed to determine the value of $R_{\theta IA}$:

$$R_{\theta}JA = R_{\theta}JC + R_{\theta}CS + R_{\theta}SA$$
 (eq. 6)

where:

 $R_{\theta,IC}$ = the junction-to-case thermal resistance,

 $R_{\theta CS}$ = the case-to-heat sink thermal resistance, and

 $R_{\theta SA}$ = the heat sink-to-ambient thermal resistance.

 $R_{\theta JC}$ appears in the package section of the data sheet. Like $R_{\theta JA}$, it too is a function of package type, $R_{\theta CS}$ and $R_{\theta SA}$ are functions of the package type, heatsink and the interface between them. These values appear in data sheets of heatsink manufacturers. Thermal, mounting, and heatsinking considerations are discussed in the ON Semiconductor application note AN1040/D, available on the ON Semiconductor website.

ORDERING INFORMATION

Device	Output Voltage	Package	Shipping [†]
NCV4269AD150G		SO-8 (Pb-Free)	98 Units/Rail
NCV4269AD150R2G		SO-8 (Pb-Free)	2500 Tape & Reel
NCV4269APD50G		SO-8 EP (Pb-Free)	98 Units/Rail
NCV4269APD50R2G		SO-8 EP (Pb-Free)	2500 Tape & Reel
NCV4269AD250G	5.0 V	SO-14 (Pb-Free)	55 Units/Rail
NCV4269AD250R2G		SO-14 (Pb-Free)	2500 Tape & Reel
NCV4269ADW50G		SO-20L (Pb-Free)	38 Units/Rail
NCV4269ADW50R2G		SO-20L (Pb-Free)	1000 Tape & Reel
NCV4269AD133R2G	3.3 V	SO-8 (Pb-Free)	2500 Tape & Reel

[†]For information on tape and reel specifications,including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



SOIC-8 NB CASE 751-07 **ISSUE AK**

DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		ERS INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27	1.27 BSC		0 BSC	
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

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DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2

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SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1 STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. PINS 2	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1 STYLE 7: PIN 1. IMPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2	3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE 2. SOURCE
PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND	PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2	PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE 2. SOURCE
PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND	PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2	PIN 1. SOURCE 2. SOURCE
6. BIAS 2 7. INPUT 8. GROUND	5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	STYLE 24: PIN 1. BASE 2. EMITTER 3. COLLECTOR/ANODE 4. COLLECTOR/ANODE 5. CATHODE 6. CATHODE 7. COLLECTOR/ANODE 8. COLLECTOR/ANODE
STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		
	PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE 8. CATHODE 8. CATHODE 8. CATHODE 8. CATHODE 9. COMMON CATHODE/VCC 9. COMMON CATHODE/VCC 1. I/O LINE 1 2. COMMON CATHODE/VCC 1. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 5 8. COMMON ANODE/GND 8. COMMON ANODE/GND 8. COMMON ANODE/GND 8. COMMON ANODE/GND 8. I/O LINE 5 8. COMMON ANODE/GND 8. SOURCE 9. I/O LINE 5 8. COMMON ANODE/GND 8. VILLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILLIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC 8. VCC 8. VCC 8. VCC 8. VCC 8. SOURCE 2 4. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2	PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 7. CATHODE, COMMON 8. N-DRAIN 8. CATHODE, COMMON 8. CATHODE 9IN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 4. GATE 2 5. DRAIN 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1 8. COMMON CATHODE/VCC 1. COMMON CATHODE/VCC 1. COMMON CATHODE/VCC 1. (/O LINE 1 2. COMMON CATHODE/VCC 1. (/O LINE 3 5. COMMON ANODE/GND 6. (/O LINE 4 7. (/O LINE 5 8. COMMON ANODE/GND 8. LINE 2 OUT 9. COMMON ANODE/GND 8. LINE 1 OUT STYLE 26: PIN 1. GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 27: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 28: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 29: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 29: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 29: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 29: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. LINE 1 OUT STYLE 29: PIN 1. ILIMIT 9. COMMON ANODE/GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. COMM

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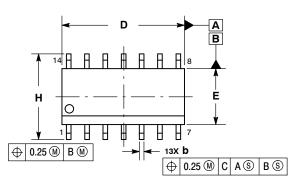
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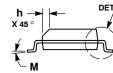
SOIC-14 NB CASE 751A-03 ISSUE L

DATE 03 FEB 2016









- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
 - ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT
- MAXIMUM MATERIAL CONDITION.
 DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE

	MILLIN	IETERS	INCHES	
DIM	MIN	MAX	MIN	MAX
Α	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
АЗ	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
Е	3.80	4.00	0.150	0.157
е	1.27	BSC	0.050 BSC	
Н	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
L	0.40	1.25	0.016	0.049
M	0 °	7°	0 °	7°

GENERIC MARKING DIAGRAM*



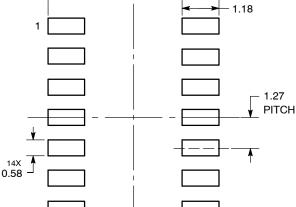
XXXXX = Specific Device Code Α = Assembly Location

WL = Wafer Lot Υ = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator. "G" or microdot " ■". may or may not be present.

- 6.50 -14X

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

C SEATING PLANE

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

SOIC-14 CASE 751A-03 ISSUE L

DATE 03 FEB 2016

STYLE 1: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. NO CONNECTION 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. NO CONNECTION 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 2: CANCELLED	STYLE 3: PIN 1. NO CONNECTION 2. ANODE 3. ANODE 4. NO CONNECTION 5. ANODE 6. NO CONNECTION 7. ANODE 8. ANODE 9. ANODE 10. NO CONNECTION 11. ANODE 12. ANODE 13. NO CONNECTION 14. COMMON CATHODE	STYLE 4: PIN 1. NO CONNECTION 2. CATHODE 3. CATHODE 4. NO CONNECTION 5. CATHODE 6. NO CONNECTION 7. CATHODE 8. CATHODE 9. CATHODE 10. NO CONNECTION 11. CATHODE 12. CATHODE 13. NO CONNECTION 14. COMMON ANODE
STYLE 5: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. NO CONNECTION 7. COMMON ANODE 8. COMMON CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 6: PIN 1. CATHODE 2. CATHODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE 7. CATHODE 8. ANODE 9. ANODE 10. ANODE 11. ANODE 12. ANODE 13. ANODE 14. ANODE	STYLE 7: PIN 1. ANODE/CATHODE 2. COMMON ANODE 3. COMMON CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. ANODE/CATHODE 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. COMMON CATHODE 12. COMMON ANODE 13. ANODE/CATHODE 14. ANODE/CATHODE	STYLE 8: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. ANODE/CATHODE 7. COMMON ANODE 8. COMMON ANODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. NO CONNECTION 12. ANODE/CATHODE 13. ANODE/CATHODE 14. COMMON CATHODE

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MECHANICAL CASE OUTLINE

NOTES 4&5

HIH

TOP VIEW

SIDE VIEW

BOTTOM VIEW

NOTE 6

Е

NOTE 6 B

A1 NOTE 8

0.20 C D

△ 0.10 C D

NOTES 4&5

0.10 C D

8X b NOTES 3&7

♦ 0.25**№** C A-B D

0.10 C

С

SEATING PLANE





SOIC-8 EP CASE 751AC ISSUE D

DATE 02 APR 2019

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS

- 2. CONTROLLING DIMENSION: MILLING LERS
 3. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE
 PROTRUSION SHALL BE 0.004 IN EXCESS OF MAXIMUM MATERIAL CONDITION.

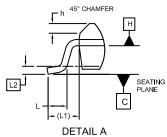
 4. DIMENSION D DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE
 BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED
 0.006 PER SIDE. DIMENSION E1 DOES NOT INCLUDE INTERLEAD FLASH OR
 PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.010 mm PER SIDE.

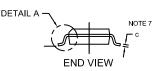
 5. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM.

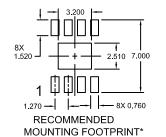
 DIMENSIONS D. AND E1 ADE DETERMINED AT THE OUTERPMOST EYTPEMES.
- DIMENSIONS D AND E1 ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 6. DATUMS A AND B ARE TO BE DETERMINED AT DATUM H.
- 8. A1 IS DEFINED AND CAPPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10 TO 0.25 FROM THE LEAD TIP.

 8. A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.









	MILLIMETERS		
DIM	MIN.	NOM	MAX.
Α	1.35	1.55	1.75
A1	İ	0.05	0.10
A2	1.35	1.50	1.65
b	0.31	0.41	0.51
С	0.17	0.21	0.23
D	4.90 BSC		
E	6.00 BSC		
E1	3.90 BSC		
е	1.27 BSC		
F	2.24	2.72	3.20
F1	0.15	0.20	0.25
G	1.55	2.03	2.51
G1	0.41	0.46	0.51
h	0.25	0.38	0.50
L	0.40	0.84	1.27
L1	1.04 REF		
L2	0.25 REF		
Ø	0°	4°	8°

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D."

GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code = Assembly Location Υ = Year ww = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present and may be in either location. Some products may not follow the Generic Marking.

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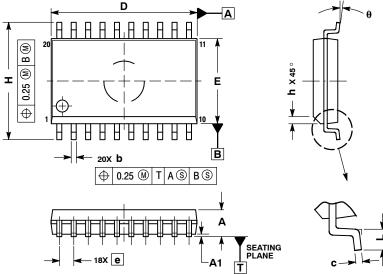




SOIC-20 WB CASE 751D-05 **ISSUE H**

DATE 22 APR 2015

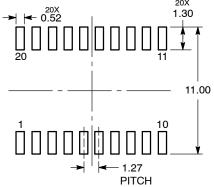
SCALE 1:1



- DIMENSIONS ARE IN MILLIMETERS.
 INTERPRET DIMENSIONS AND TOLERANCES.
- PER ASME Y14.5M, 1994.
 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- PROTRUSION.
 MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
- DIMENSION B DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF B DIMENSION AT MAXIMUM MATERIAL

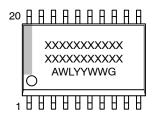
	MILLIMETERS		
DIM	MIN	MAX	
Α	2.35	2.65	
A1	0.10	0.25	
b	0.35	0.49	
С	0.23	0.32	
D	12.65	12.95	
E	7.40	7.60	
е	1.27 BSC		
Н	10.05	10.55	
h	0.25	0.75	
L	0.50	0.90	
A	0 °	7 °	

RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

WL = Wafer Lot ΥY = Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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DESCRIPTION:	SOIC-20 WB		PAGE 1 OF 1

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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